

# SIGMATEST® 2.068

- $\sqrt{\phantom{a}}$  Determining physical and technological material properties
- $\sqrt{}$  Monitoring the condition of highly stressed parts
- √ Material-mix testing
- $\checkmark$  Sorting of metals and alloys
- $\sqrt{}$  In-process inspection in industrial, metallurgical and metalworking plants
- $\sqrt{}$  Incoming inspection
- $\sqrt{\text{Aircraft maintenance inspection}}$
- √ Verification of the age-hardening condition of aluminum used in aircraft construction



SIGMATEST 2.068 - The eddy-current instrument for conductivity measurements on all non-ferrous metals

### **Application**

- \* Absolute measurement of the electrical conductivity of non-ferrous metals
- \* Determination of metal purity
- \* Monitoring of metal homogeneity
- \* Monitoring of strength and hardness
- \* Determination of the phosphorus content in copper
- Monitoring of the casting process (polarization) of copper

- \* Monitoring of separation processes, e.g. for Cu-Cr alloys
- \* Measurements possible at high material temperature by lining with ceramic wafers up to a thickness of 500 µm (.02 inch)
- \* Detection of heat damage in aluminum alloys (e.g. in the aircraft maintenance)
- \* Scrap sorting

### Characteristics

\* Two versions: SIGMATEST Ec for standard applications SIGMATEST D with extended scope of functions

# Common characteristics of SIGMATEST Ec and SIGMATEST D

- \* Fast and reliable determination of measured values at high accuracy
- \* Large measuring range from 0.5 to 65 MS/m (1% to 112% IACS)
- \* Clearance compensation up to 500 µm (.02 inch)
- \* Consistently high accuracy on workpieces of various thickness
- \* Four selectable measuring frequencies
- \* Consistently high accuracy through to the edge of the material
- \* Probe and probe cable can be replaced separately

- \* Recalibration necessary only when requested by the instrument
- \* Serial interface RS 232 for data output to a PC or printer
- \* Spray-water-protected housing
- \* Leak-proof battery compartment

### Additional characteristics of the SIGMATEST D

- \* Statistical evaluation programs
- \* Measured values memory for 10,000 measured values, buffered by battery
- \* Memory card for storing and cataloging measured values and for storing and reloading instrument settings
- \* Temperature compensation by a temperature sensor integrated in the probe or with the aid of an external temperature sensor

### **Function**

# Measurement principle

The instrument operates on the basis of the eddycurrent method. It determines the electrical conductivity of non-ferromagnetic metals. This permits conclusions to be drawn as regards to the composition, structure and condition of the material.

### Operation

The instrument is ready for use immediately after switching on. The SIGMATEST Ec offers one standard operating mode and is thus particularly easy to operate. The SIGMATEST D has a program selection feature permitting the operator to call various operating modes and special additional functions.

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### **Operating modes**

| Mode             | Function                                    | Measured<br>value repre-<br>sentation |     | SIGMATEST<br>D |
|------------------|---|---------------------------------------|-----|----------------|
| Standard         | Conductivity                                | Touch mode                            | Yes | Yes            |
| mode measurement |   | Free run                              | No  | Yes            |
| Sort<br>mode     | Sorting into four classes                   | Touch mode                            | No  | Yes            |
| Limit<br>mode    | Sorting with an upper limit and lower limit | Touch mode                            | No  | Yes            |

### Standard mode with touch-mode representation

When the probe is lowered onto the workpiece, the instrument records the measured value and displays it on the display until the next time the probe is lowered onto material.

### Frequency selection

Four different frequencies of 60, 120, 240 and 480 kHz permit measurements to be conducted on work-pieces of various thickness with constantly high accuracy. This eliminates the need to use the correction factors for thin aluminum sheets.

### Clearance compensation

The automatical clearance compensation allows measurements even if there are non-conductive layers on the workpiece, e.g. dust, enamel or paint coatings up to a thickness of 500 µm (.02 inch).

### **Temperature monitoring**

The calibration standards are calibrated at a tempperature of 20 °C (68 °F). Therefore the SIGMATEST achieves its highest measuring accuracy at this temperature.

Changes in temperature influence both the probe response and the conductivity of the material to be tested. They can be corrected by recalibration.

The instrument monitors the temperature with the aid of a temperature sensor integrated in the probe and signals automatically when it is necessary to recalibrate.

### Additional functions of the SIGMATEST D

### Standard mode with free-run representation

Measurement is conducted continuously in this operating mode. The display always shows the current measured value.

### Sorting limits in Sort and Limit operating modes

Different conductivity classes can be defined by means of freely selectable limits. Four classes can be defined in Sort mode and one class in Limit mode.

### Internal memory

Measured values and instrument settings can be stored, managed and reloaded in the internal memory. The memory has a capacity for up to 10,000 measured values.

### External storing on a memory card

Measured values and instrument settings can be copied onto a memory card and reloaded from it. This allows the results of regular inspections to be cataloged over years.

### Statistical evaluation

The SIGMATEST D permits the following statistical evaluation:

- \* Mean value, standard deviation and number of the measured values of a measuring series
- \* Distribution of the measured values in the conductivity classes in Sort and Limit operating modes

The results can be shown on the display and stored together with the instrument setting.

### Temperature compensation

The SIGMATEST D compensates for temperature related conductivity variations. There are two ways:

- \* Compensation with a temperature coefficient stored at the factory
- \* Compensation with a temperature coefficient input by the operator. This allows optimization of the compensation for specific materials

The necessary temperature measurement can be performed optionally by using the temperature sensor integrated in the probe or by connecting an external temperature sensor. An external temperature sensor is recommended if the material temperature differs from the probe temperature.

### Construction

### SIGMATEST Ec testing device

- Easy-to-operate, self-explanatory function keypad.
   No multi-function keys.
- Light, ergonomically formed measuring instrument for laboratory and field use.
- \* Clear, almost reflection-free LCD display. The instrument setting and measured value are visible at a glance.
- \* Visual and/or audible signaling for various events, e.g. limit transgression, calibration recall, battery discharge, etc.

### Separate connectors for:

- \* Probe
- \* RS 232 interface
- Power supply
- Compartment with two removable calibration standards.
- \* Leak-proof battery compartment for four Ni/Cd "AA" re-chargeable batteries or four standard "AA" alkaline cells.
- \* Brief operating instructions printed on the underside of the instrument.
- \* Rating plate for instrument and probe identification number on the underside of the instrument.

### SIGMATEST D testing device

As for SIGMATEST Ec testing device, but also:

- Connector for external temperature sensor
- Memory card slot in the compartment beneath the calibration standards

The keypad assignment differs from that on the SIGMA-TEST Ec. Keys have a dual assignment, thus permitting you to call additional functions.

### Standard functional sets and standard components

Figures 3 and 4 show an overview of the standard components available for the SIGMATEST Ec and SIGMATEST D and the combination of the most important components into functional sets. In the following, you find the description of the main components.

### Standard functional sets

The standard functional sets contain everything that is needed for normal use of the instrument. The sets with 230V power supply unit are scheduled for countries with mains power in accordance with DIN IEC 38. The sets without power supply unit are intended for countries whose mains power differs from this standard. Your local FOERSTER representative can supply you with an appropriate power supply.

# Accessories and services for SIGMATEST Ec and SIGMATEST D

### **Power supply**

The instrument can be operated alternatively with:

- \* Four Ni/Cd "AA" rechargeable batteries
- \* Four "AA" alkaline cells (1.5V IEC LR6)
- \* A power supply

### **Carrying accessories**

- \* Case For transportation and storage of the instrument, probes, and accessories.
- \* Carrying bag For wearing over the shoulder. Accomodates the instrument for mobile use.

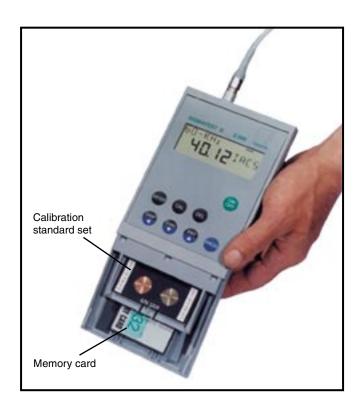


 Figure 2 - SIGMATEST D, housing opened, calibration standard set and memory card visible

#### Probes and accessories

A suitable probe and probe cable for connection to the testing device are necessary for operation.

### \* Probe D=14 mm with handgrip

Standard probe with handgrip and an Allen key for fixing the handgrip. The handgrip helps to isolate the probe from the operator's body temperature and thus ensures higher measurement accuracy. The handgrip and Allen key can be reordered as spare parts.

### \* Set-down prism for probe D=14 mm

The set-down prism serves as a support when testing round stock.

### \* Angle probe D=14 mm

Probe with a handgrip angled at 90° for testing at less accessible points.

### \* Probe D=8 mm with handgrip with prism

Probe for testing at small measuring areas and of material with a small radius. The handgrip and prism can be reordered as spare parts.

### Conductivity standards and accessories

Conductivity standards serve for calibrating the instrument before use. All standards offered are certified and are themselves calibrated on the basis of national standards so that all measurements are traceable back in compliance with the requirements of ISO 9000.

# \* Conductivity standard set 58MS/m (100% IACS), 2.39MS/m (4.12% IACS)

This set is supplied together with the standard functional sets and consists of materials with conductivity values that lie at both ends of the measuring range. Calibration using this set is suitable for measurements over the entire measuring range.

### \* Calibration standard set

This calibration set is available as an option. CALIBRATION STANDARD SET (3 STDS.) SPECIAL, 17.40 MS/m (30% IACS); 24.36 MS/m (42% IACS); 34.8 MS/m (60% IACS)

The SIGMATEST features a serial RS 232 interface for connection to a printer or computer. All printers can be connected which have a serial interface and are compatible with the Epson FX8xx series.

### \* Interface cable AT PC, printer

Special cable, required for connection of a computer or printer to the SIGMATEST. The adapter set for printer or cable is required additionally for connection of a printer.

### \* Printer with RS232C

Epson printer available for stationary use.

### Accessories, suitable only for SIGMATEST D

### \* Memory Card 32k x 8 bit

The memory card is used for storing and archiving of measured data, instrument settings, or measuring series.

### \* Software PC

Program for transfer and storage of individual data or entire data records to a PC.

### **Temperature sensor**

Option for measuring the temperature of the material under test and for compensating for the temperature-related conductivity variation. A temperature sensor should be used if the material temperature differs from the probe temperature.

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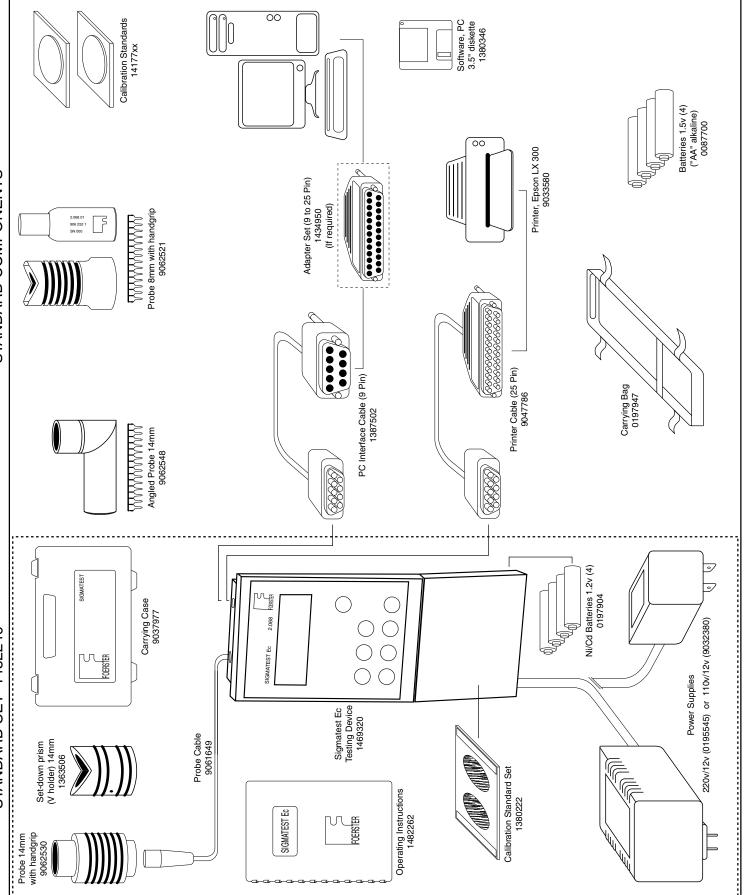


Figure 3 SIGMATEST Ec - Overview of the standard components

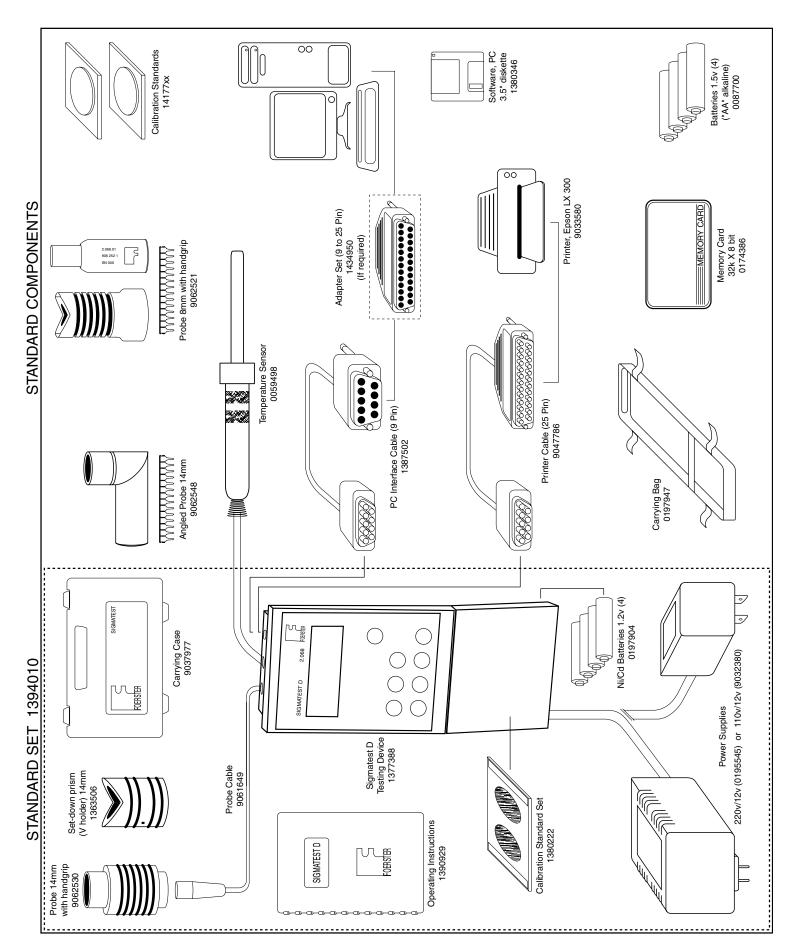


Figure 4 SIGMATEST D - Overview of the standard components

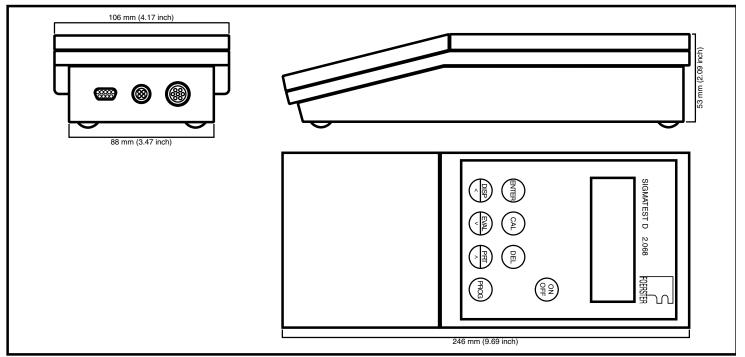


Figure 5 Dimension drawing SIGMATEST

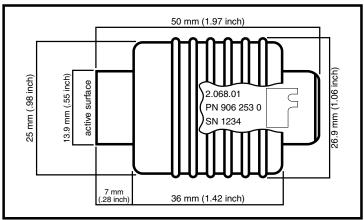


Figure 6 Dimension drawing probe 14mm

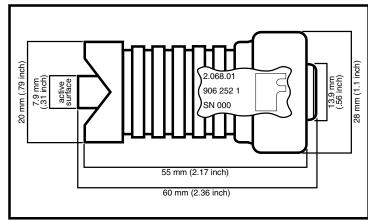


Figure 7 Dimension drawing probe 8mm

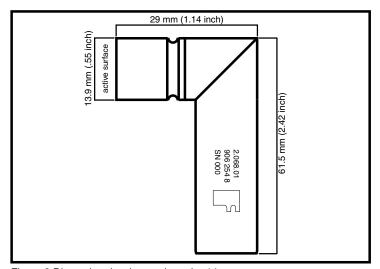


Figure 8 Dimension drawing angle probe 14mm

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### **Technical data**

| Feature  | SIGMATEST Ec   | SIGMATEST D   |
|--|--|---|
| Measuring ranges, selectable <sup>1</sup>  | 0.5 to 65 MS/m or 1 to 112% IACS <sup>2</sup>  |   |
| Absolute accuracy  | depending upon temperature, up to $\pm$ 1.5% of measured value   | ± 1% of measured value  |
| Resolution:<br>for 60, 120 and 240 kHz<br>for 480 kHz  | $\pm$ 0.1% of measured value<br>$\pm$ 0.1% for .5< $\sigma$ <30 MS/m,<br>$\pm$ 0.2% for 30< $\sigma$ <45 MS/m,<br>$\pm$ 0.3% for $\sigma$ >45 MS/m |   |
| Clearance compensation   | to 500 µm (.02 inch)   |   |
| Frequencies, selectable  | 60, 120, 240, 480 kHz  |   |
| LCD display  | 4-digit, 7-segment display for the measured value 12 x 16 segment for instrument settings 10 status displays                                       |   |
| Keypad   | membrane keypad with 8 keys  | as for SIGMATEST Ec, but with different assignment  |
| Interfaces for: probe serial RS 232 interface power supply unit external temperature sensor memory card            | 7-pole Lemo socket<br>9-pole MDS<br>jack connector 3.5mm ø<br>no<br>no   | 7-pole Lemo socket 9-pole MDS jack connector 3.5 mm Ø 4-pole Fischer socket 34-pole interface |
| Operating duration with one set of full:  Alkaline batteries "AA", 4 ea.  Ni/Cd rechargeable batteries, "AA" 4 ea. | 8 hours<br>8 hours   |   |
| Memory<br>internal RAM<br>external memory card   | no<br>no   | 32 kBytes<br>32 kBytes  |
| Protection class<br>instrument<br>probe  | IP 53 (with closed compartment cover) IP 53  |   |
| Permitted ambient temperature instrument probe material temperature  | e<br>0 to +55° C<br>0 to +55° C<br>0 to +70° C   |   |
| Mass measuring instrument  | 0.75 kg with accumulators 0.65 kg without accumulators   |   |
| Dimensions measuring instrument and probes   | see figures 5 to 8   |   |

<sup>?</sup> with probe D=8 and a frequency of 60 or 120 kHz, the measuring range is restricted to 2.5 to 58 MS/m (4 to 100% IACS)  $^2$  IACS = International Annealed Copper Standard, 100% IACS = 58 MS/m

# **SIGMATEST D**

### STANDARD SETS

| Description   | Part Number | ID Number |
|---|-------------|-----------|
| SIGMATEST D WITH 14MM PROBE<br>110V OR 220V (CUSTOMER TO SPECIFY)<br>NSN NO. 6635 01 420 5318 KIT   | 2.068.82    | 1394010   |
| Consisting of:  |             |           |
| 1 SIGMATEST D testing device 1 Operating instructions 1 Probe 14mm with hand grip 1 Set-down prism 1 Probe cable 1 Calibration standard set 4 Ni/Cd batteries (1.2v) 1 Case 1 Power supply 220v/12v -or- 1 Power supply 110v/12v (with 1 foam insert) |             |           |

# **SIGMATEST D WITH 8MM PROBE** 110V OR 220V (CUSTOMER TO SPECIFY)

2.068.83

9033718

# Consisting of:

- 1 SIGMATEST D testing device
- 1 Operating instructions
- 1 Probe 8mm with hand grip
- 1 Probe cable
- 1 Calibration standard set
- 4 Ni/Cd batteries (1.2v)
- 1 Case
- 1 Power supply 220v/12v

1 Power supply 110v/12v (with 1 foam insert)

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### SIGMATEST D

### STANDARD SETS

| Description  | Part Number | ID Number |  |
|--|-------------|-----------|--|
| SIGMATEST D WITH 14MM PROBE<br>110V OR 220V (CUSTOMER TO SPECIFY)<br>NATO NO. 6635 90 980 1488 KIT | 2.068.84    | 1472437   |  |
| Consisting of:   |             |           |  |
| 1 SIGMATEST D testing device   |             |           |  |

- 1 Operating instructions
- 1 Probe 14mm with hand grip
- 1 Set-down prism
- 1 Probe cable
- 1 Calibration standard set
- 4 Ni/Cd batteries (1.2v)
- 1 Case
- 1 Temperature sensor
- 1 Interface cable AT
- 1 Software (PC)
- 1 Memory card
- 1 Power supply 220v/12v

### -or-

1 Power supply 110v/12v (with 1 foam insert)

# SIGMATEST D (WITH AUTOMATIC SWITCH OFF DISABLED), WITH 14MM PROBE, 110V OR 220V (CUSTOMER TO SPECIFY) KIT

2.068.86

9063170

### Consisting of:

- 1 SIGMATEST D testing device with Auto Switch Off disabled
- 1 Operating instructions
- 1 Probe 14mm with hand grip
- 1 Set-down prism
- 1 Probe cable
- 1 Calibration standard set
- 4 Ni/Cd batteries (1.2v)
- 1 Case
- 1 Power supply 220v/12v

1 Power supply 110v/12v (with 1 foam insert)

# **SIGMATEST Ec**

### STANDARD SETS

| Description  | Part Number | ID Number |
|--|-------------|-----------|
| SIGMATEST Ec WITH 14MM PROBE<br>110V OR 220V (CUSTOMER TO SPECIFY)<br>NSN NO. 6635 01 420 5322 KIT   | 2.068.92    | 1482246   |
| Consisting of:   |             |           |
| 1 SIGMATEST Ec testing device 1 Operating instructions 1 Probe 14mm with hand grip 1 Set-down prism 1 Probe cable 1 Calibration standard set 4 Ni/Cd batteries (1.2v) 1 Case 1 Power supply 220v/12v -or- 1 Power supply 110v/12v (with 1 foam insert) |             |           |

# SIGMATEST Ec WITH 8MM PROBE 110V OR 220V (CUSTOMER TO SPECIFY)

2.068.90

9033726

# Consisting of:

- 1 SIGMATEST Ec testing device
- 1 Operating instructions
- 1 Probe 8mm with hand grip
- 1 Probe cable
- 1 Calibration standard set
- 4 Ni/Cd batteries (1.2v)
- 1 Case
- 1 Power supply 220v/12v

-or-

1 Power supply 110v/12v (with 1 foam insert)

# SIGMATEST D/Ec

# STANDARD COMPONENTS

| Description   | Part Number  | ID Number  |
|---|--|--|
|   |  |  |
| STANDARDS   |  |  |
| Calibration Standard set (2 STDS.)<br>2.39 MS/m (4.12% IACS); 58 MS/m (100% IACS)   | 2.068.01   | 1380222  |
| Calibration Special Standard set (3 STDS.)<br>17.40 MS/m (30% IACS); 24.36 MS/m (42% IACS);<br>34.8 MS/m (60% IACS)   | 2.068.01   | 9048944  |
| Conductivity Standard .6 MS/m (1 IACS) Conductivity Standard 4.4 MS/m (8 IACS) Conductivity Standard 16 MS/m (28 IACS) Conductivity Standard 17 MS/m (29 IACS) Conductivity Standard 22 MS/m (38 IACS) Conductivity Standard 30 MS/m (52 IACS) Conductivity Standard 36 MS/m (62 IACS) Conductivity Standard 58 MS/m (100 IACS) | 2.068.01<br>2.068.01<br>2.068.01<br>2.068.01<br>2.068.01<br>2.068.01<br>2.068.01 | 1417703<br>1417720<br>9063153<br>1417754<br>1417762<br>1417797<br>1417770<br>1417789 |
| NOTES: 1) All standards above are approximate in value 2) Measurement of uncertainty: + OR - 0.5%   |  |  |

# **ACCESSORIES**

| Temperature Sensor                                 | PRD52697B | 0059498 |
|--|-----------|---------|
| Memory Card, 32k x 8 bit                           | BN-032MCE | 0174386 |
| Printer, Epson LX300                               | C130001   | 9033580 |
| Printer Cable, 2M (25 pin)                         | 2.068US   | 9047786 |
| Adapter Set, 9 to 25 pin (for PC)                  | 2.068.01  | 1434950 |
| Interface Cable, PC AT (9 pin)                     | 2.068.01  | 1387502 |
| Software PC, 3-1/2" diskette (for sending measured | 2.068.01  | 1380346 |
| values from the Sigmatest to a PC)                 |           |         |

# SIGMATEST D/Ec

# STANDARD COMPONENTS

| Description  | Part Number   | ID Number  |
|--|---|--|
|  |   |  |
| INSTRUMENTS  |   |  |
| Leaflet Operating Instructions, SIGMATEST D Operating Instructions, SIGMATEST Ec SIGMATEST D testing device SIGMATEST Ec testing device SIGMATEST D testing device, with Automatic Switch Off disabled Case Carrying Bag | 2.068 UA01/E<br>2.068 UA06/E<br>2.068 CUA06/E<br>2.068.01<br>2.068.01<br>2.068.01<br>2.068.01<br>2.068.01 | 1381997<br>1390929<br>1482262<br>1377388<br>1469320<br>9063161<br>9037977<br>0197947 |
| POWER SUPPLIES   |   |  |
| Ni/Cd Battery (1.2v) Battery, 1.5v (AA) Power Supply 220v/12v Power Supply 110v/12v  | VH1200AA<br>PC1500<br>11.7906<br>PIDB-201   | 0197904<br>0087700<br>0195545<br>9032380   |
| PROBES   |   |  |
| Probe, Standard, 14mm with handgrip<br>Probe, 8mm with handgrip<br>Probe, 14mm angled<br>Set-down Prism (V-holder) 14mm<br>Set-down Prism (V-holder) 8mm<br>Probe handgrip<br>Probe cable                                | 2.068.01<br>2.068.01<br>2.068.01<br>2.068.01<br>2.068.01<br>2.068.01<br>2.068.01                          | 9062530<br>9062521<br>9062548<br>1363506<br>1461834<br>1419404<br>9061649            |

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